

TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

TC74HC4024AP, TC74HC4024AF**7 - STAGE BINARY COUNTER**

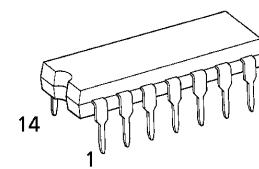
The TC74HC4024A is a high speed CMOS 7 - STAGE BINARY COUNTER fabricated with silicon gate C²MOS technology.

It achieves the high speed operation similar to equivalent LSTTL while maintaining the CMOS low power dissipation. A negative transition on the \overline{CK} input brings one increment to the counter.

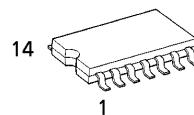
A CLR input is used to reset the counter to the all low level state. A high level at CLR accomplishes the reset function. All divided output stages are provided, and the last stage, 1/128 divided frequency will be obtained. All inputs are equipped with protection circuits against static discharge or transient excess voltage.

FEATURES :

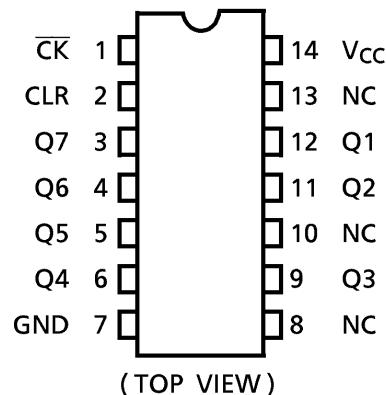
- High Speed..... $f_{MAX} = 70\text{MHz}$ (typ.) at $V_{CC} = 5\text{V}$
- Low Power Dissipation..... $I_{CC} = 4\mu\text{A}$ (Max.) at $T_a = 25^\circ\text{C}$
- High Noise Immunity..... $V_{NIH} = V_{NIL} = 28\%$ V_{CC} (Min.)
- Output Drive Capability.....10 LSTTL Loads
- Symmetrical Output Impedance..... $|I_{OH}| = |I_{OL}| = 4\text{mA}$ (Min.)
- Balanced Propagation Delays..... $t_{PLH} \approx t_{PHL}$
- Wide Operating Voltage Range..... V_{CC} (opr.) = $2\text{V} \sim 6\text{V}$
- Pin and Function Compatible with 4024B



P (DIP14-P-300-2.54)
Weight : 0.96g (Typ.)

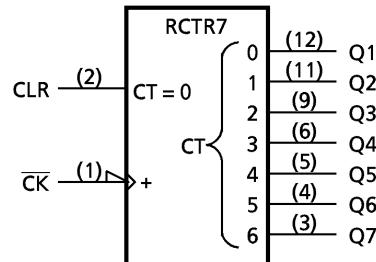


F (SOP14-P-300-1.27)
Weight : 0.18g (Typ.)

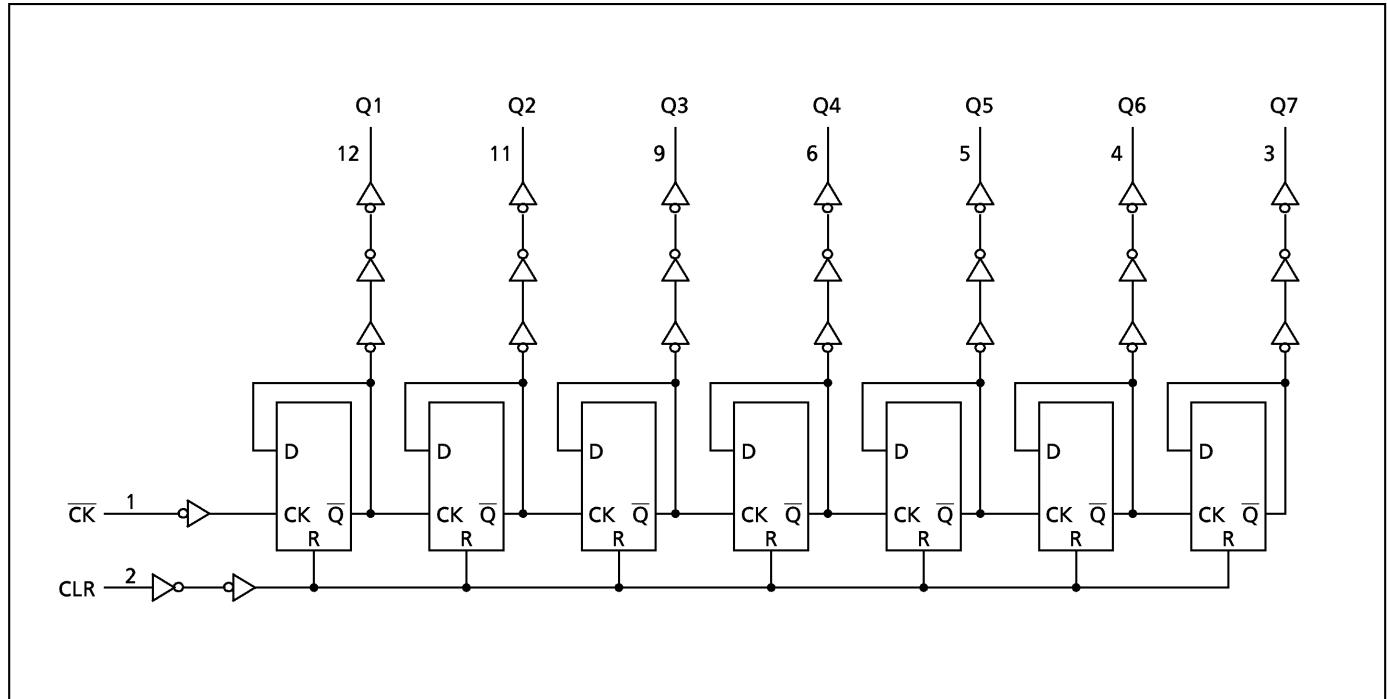
PIN ASSIGNMENT**TRUTH TABLE**

INPUTS		OUTPUT STATUS
CK	CLR	
X	H	ALL OUTPUTS = "L"
	L	NO CHANGE
	L	ADVANCE TO NEXT STAGE

X : Don't Care

IEC LOGIC SYMBOL

SYSTEM DIAGRAM



ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage Range	V_{CC}	-0.5~7	V
DC Input Voltage	V_{IN}	-0.5~ $V_{CC} + 0.5$	V
DC Output Voltage	V_{OUT}	-0.5~ $V_{CC} + 0.5$	V
Input Diode Current	I_{IK}	± 20	mA
Output Diode Current	I_{OK}	± 20	mA
DC Output Current	I_{OUT}	± 25	mA
DC V_{CC} /Ground Current	I_{CC}	± 50	mA
Power Dissipation	P_D	500 (DIP)* / 180 (SOP)	mW
Storage Temperature	T_{STG}	-65~150	°C

*500mW in the range of $T_a = -40^{\circ}\text{C} \sim 65^{\circ}\text{C}$. From $T_a = 65^{\circ}\text{C}$ to 85°C a derating factor of $-10\text{mW}/^{\circ}\text{C}$ shall be applied until 300mW.

RECOMMENDED OPERATING CONDITIONS

PARAMETER	SYMBOL	VALUE	UNIT
Supply Voltage	V_{CC}	2~6	V
Input Voltage	V_{IN}	0~ V_{CC}	V
Output Voltage	V_{OUT}	0~ V_{CC}	V
Operating Temperature	T_{OPR}	-40~85	°C
Input Rise and Fall Time	t_r, t_f	0~1000 ($V_{CC} = 2.0\text{V}$) 0~500 ($V_{CC} = 4.5\text{V}$) 0~400 ($V_{CC} = 6.0\text{V}$)	ns

DC ELECTRICAL CHARACTERISTICS

PARAMETER	SYMBOL	TEST CONDITION	V_{CC} (V)	Ta = 25°C			Ta = -40~85°C		UNIT
				MIN.	TYP.	MAX.	MIN.	MAX.	
High - Level Input Voltage	V_{IH}		2.0 4.5 6.0	1.50 3.15 4.20	— — —	— — —	1.50 3.15 4.20	— — —	V
Low - Level Input Voltage	V_{IL}		2.0 4.5 6.0	— — —	— — —	— — —	0.50 1.35 1.80	— — —	V
High - Level Output Voltage	V_{OH}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OH} = -20\mu\text{A}$	2.0 4.5 6.0	1.9 4.4 5.9	2.0 4.5 6.0	— — —	1.9 4.4 5.9	— — —
			$I_{OH} = -4\text{ mA}$ $I_{OH} = -5.2\text{ mA}$	4.5 6.0	4.18 5.68	4.31 5.80	— —	4.13 5.63	— —
Low - Level Output Voltage	V_{OL}	$V_{IN} = V_{IH}$ or V_{IL}	$I_{OL} = 20\mu\text{A}$	2.0 4.5 6.0	— — —	0.0 0.0 0.0	0.1 0.1 0.1	— — —	0.1 0.1 0.1
			$I_{OL} = 4\text{ mA}$ $I_{OL} = 5.2\text{ mA}$	4.5 6.0	— —	0.17 0.18	0.26 0.26	— —	0.33 0.33
Input Leakage Current	I_{IN}	$V_{IN} = V_{CC}$ or GND	6.0	—	—	± 0.1	—	± 1.0	μA
Quiescent Supply Current	I_{CC}	$V_{IN} = V_{CC}$ or GND	6.0	—	—	4.0	—	40.0	

TIMING REQUIREMENTS (Input $t_r = t_f = 6\text{ns}$)

PARAMETER	SYMBOL	TEST CONDITION	$V_{CC}(\text{V})$	$T_a = 25^\circ\text{C}$		$T_a = -40\text{--}85^\circ\text{C}$	UNIT
				TYP.	LIMIT	LIMIT	
Minimum Pulse Width (CK)	$t_{W(L)}$ $t_{W(H)}$		2.0	—	75	95	ns
			4.5	—	15	19	
			6.0	—	13	16	
Minimum Pulse Width (CLR)	$t_{W(H)}$		2.0	—	75	95	ns
			4.5	—	15	19	
			6.0	—	13	16	
Minimum Removal Time	t_{rem}		2.0	—	25	30	
			4.5	—	5	6	
			6.0	—	5	5	
Clock Frequency	f		2.0	—	6	5	MHz
			4.5	—	31	25	
			6.0	—	36	29	

AC ELECTRICAL CHARACTERISTICS ($C_L = 15\text{pF}$, $V_{CC} = 5\text{V}$, $T_a = 25^\circ\text{C}$, Input $t_r = t_f = 6\text{ns}$)

PARAMETER	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Output Transition Time	t_{TLH} t_{THL}		—	4	8	ns	
Propagation Delay Time (CK-Q1)	t_{PLH} t_{PHL}		—	13	20		
Propagation Delay Time (Qn-Qn+1)	Δt_{pd}		—	4	9		
Propagation Delay Time (CLR-Qn)	t_{PHL}		—	13	20		
Maximum Clock Frequency	f_{MAX}		34	70	—	MHz	

AC ELECTRICAL CHARACTERISTICS ($C_L = 50\text{pF}$, Input $t_r = t_f = 6\text{ns}$)

PARAMETER	SYMBOL	TEST CONDITION	$V_{CC}(\text{V})$	$T_a = 25^\circ\text{C}$		$T_a = -40\text{--}85^\circ\text{C}$		UNIT
				MIN.	TYP.	MAX.	MIN.	
Output Transition Time	t_{TLH} t_{THL}		2.0	—	30	75	—	95
			4.5	—	8	15	—	19
			6.0	—	7	13	—	16
Propagation Delay Time (CK-Q1)	t_{PLH} t_{PHL}		2.0	—	60	120	—	150
			4.5	—	16	24	—	30
			6.0	—	13	20	—	26
Propagation Delay Time (Qn-Qn+1)	Δt_{pd}		2.0	—	24	60	—	75
			4.5	—	6	12	—	15
			6.0	—	5	10	—	13
Propagation Delay Time (CLR-Qn)	t_{PHL}		2.0	—	50	120	—	150
			4.5	—	16	24	—	30
			6.0	—	13	20	—	26
Maximum Clock Frequency	f_{MAX}		2.0	6	17	—	5	—
			4.5	31	63	—	25	—
			6.0	36	73	—	29	—
Input Capacitance	C_{IN}		—	5	10	—	10	pF
Power Dissipation Capacitance	$C_{PD}(1)$		—	36	—	—	—	

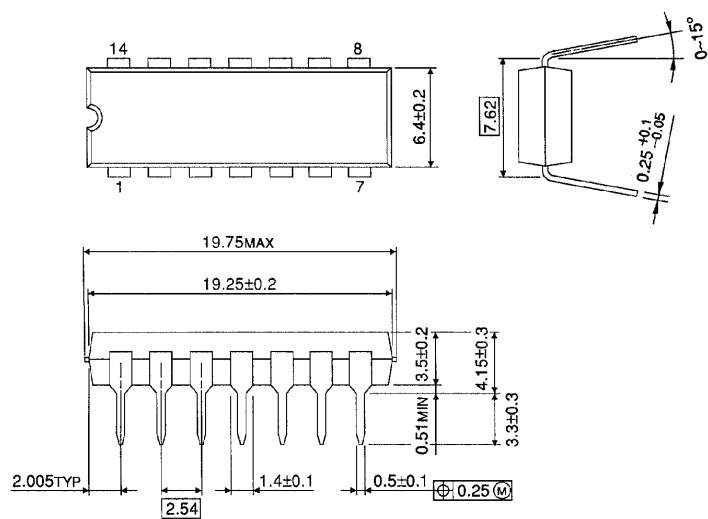
Note(1) C_{PD} is defined as the value of the internal equivalent capacitance which is calculated from the operating current consumption without load.

Average operating current can be obtained by the equation :

$$I_{CC(\text{opr})} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC}$$

DIP 14PIN PACKAGE DIMENSIONS (DIP14-P-300-2.54)

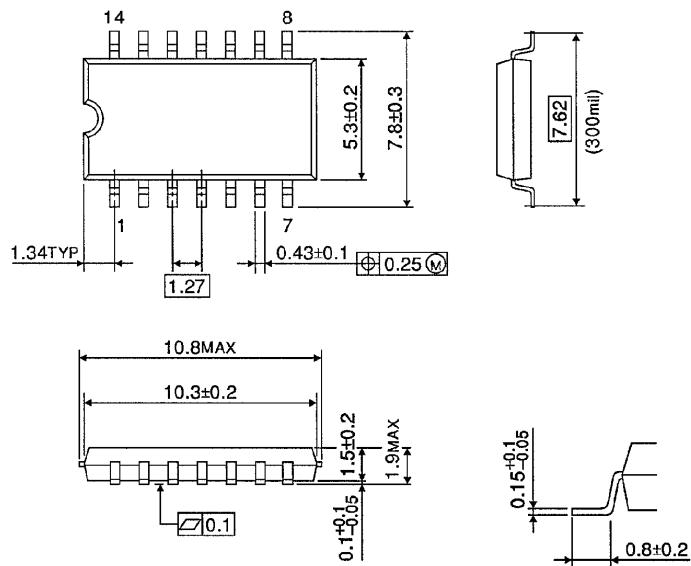
Unit in mm



Weight : 0.96g (Typ.)

SOP 14PIN (200mil BODY) PACKAGE DIMENSIONS (SOP14-P-300-1.27)

Unit in mm



Weight : 0.18g (Typ.)

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